

CEP703ALS2/CEB703ALS2

ELECTRICAL CHARACTERISTICS ($T_C=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	I_{DS}	$V_{DS}=24V, V_{GS}=0V$			10	μA
Gate-Body Leakage	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
ON CHARACTERISTICS^a						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1	1.7	3	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=25A$		14	17	$m\Omega$
		$V_{GS}=4.5V, I_D=10A$		22	30	$m\Omega$
On-State Drain Current	$I_{D(ON)}$	$V_{GS}=10V, V_{DS}=10V$	60			A
Forward Transconductance	g_F	$V_{DS}=10V, I_D=25A$		30		S
DYNAMIC CHARACTERISTICS^b						
Input Capacitance	C_{iss}	$V_{DS}=15V, V_{GS}=0V$ $f=1.0MHz$		1150	1500	pF
Output Capacitance	C_{oss}			540	700	pF
Reverse Transfer Capacitance	C_{rss}			230	300	pF
SWITCHING CHARACTERISTICS^b						
Turn-On Delay Time	$t_{D(ON)}$	$V_{DD}=15V,$ $I_D=25A,$ $V_{GS}=10V,$ $R_{GEN}=24\Omega$		18	23	ns
Rise Time	t_r			120	180	ns
Turn-Off Delay Time	$t_{D(OFF)}$			80	120	ns
Fall Time	t_f			60	165	ns
Total Gate Charge	Q_g	$V_{DS}=10V, I_D=25A,$ $V_{GS}=10V$		30	50	nC
Gate-Source Charge	Q_{gs}			6		nC
Gate-Drain Charge	Q_{gd}			7		nC

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BODY DIODE & SCHOTTKY DIODE RATINGS AND CHARACTERISTICS

Parameter	Symbol	Condition	Min	Typ	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS^a						
Body Diode Forward Voltage	V _{SD}	V _{GS} = 0V, I _S = 25A			1.3	V
Schottky Forward Voltage	V _F	I _F =2A, T _C =25°C			0.55	V
Average Forward Rectified Current	I _{F(AV)}				2	A

Notes

a. Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2\%$.

b. Guaranteed by design, not subject to production testing.

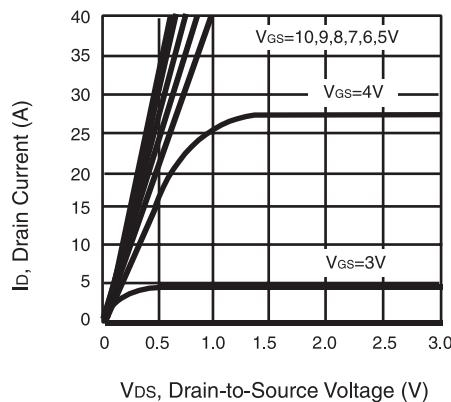


Figure 1. Output Characteristics

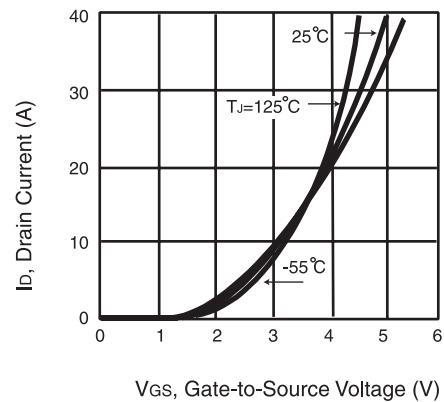


Figure 2. Transfer Characteristics

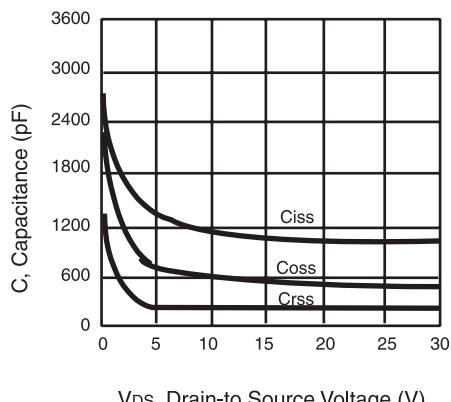


Figure 3. Capacitance

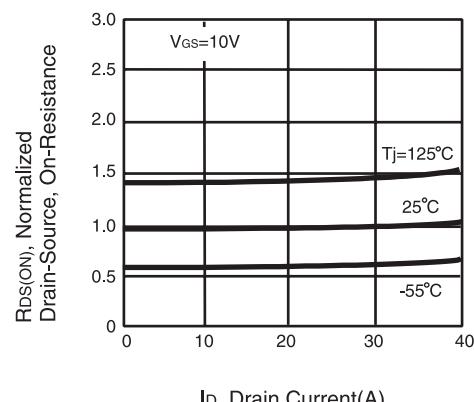


Figure 4. On-Resistance Variation with Drain Current and Temperature

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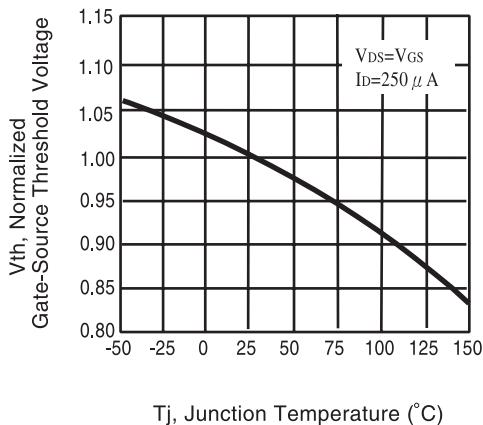


Figure 5. Gate Threshold Variation with Temperature

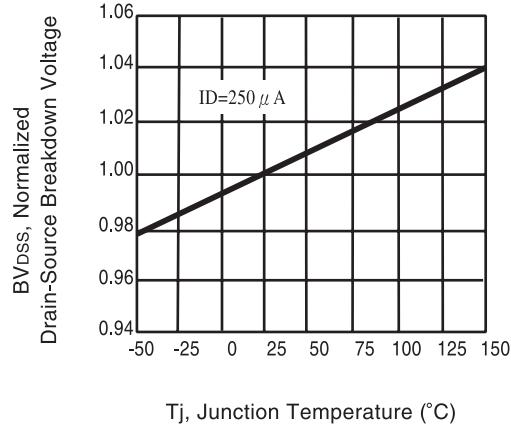


Figure 6. Breakdown Voltage Variation with Temperature

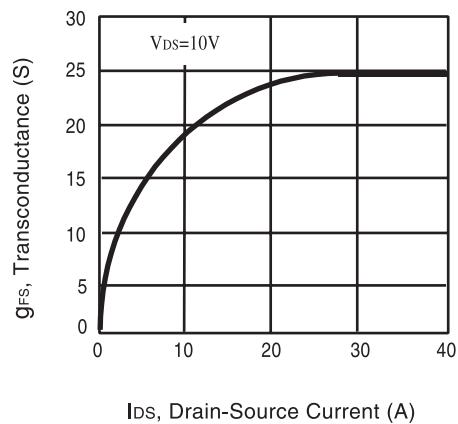


Figure 7. Transconductance Variation with Drain Current

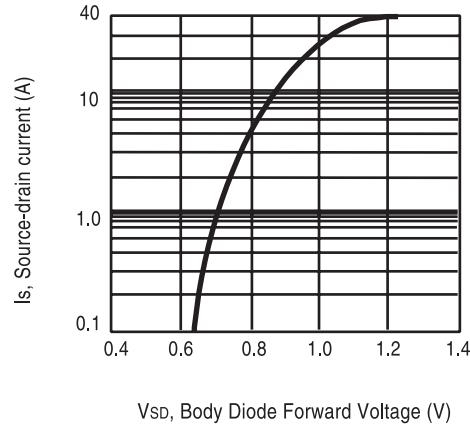


Figure 8. Body Diode Forward Voltage Variation with Source Current

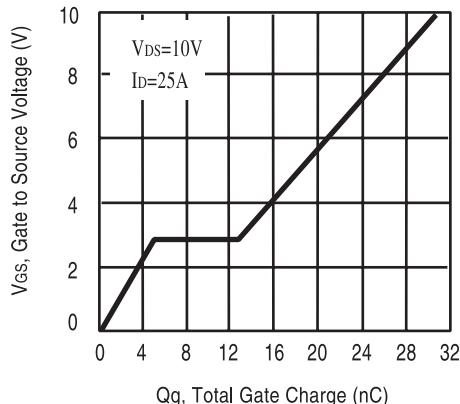


Figure 9. Gate Charge

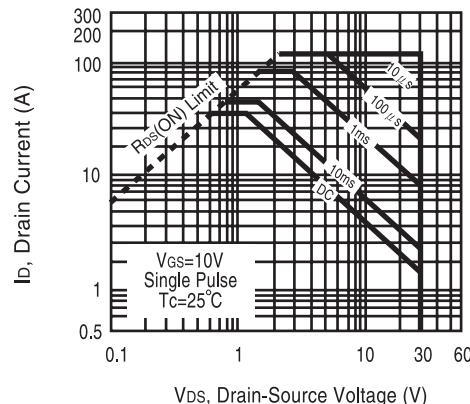
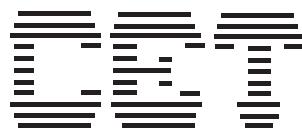


Figure 10. Maximum Safe Operating Area

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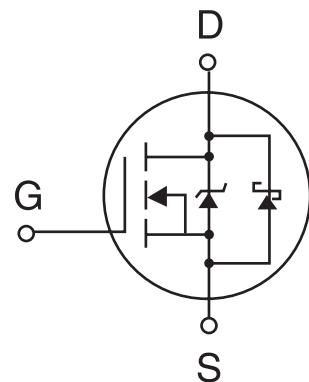
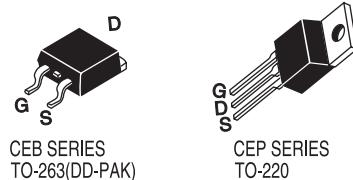


PRELIMINARY

N-Channel Logic Level Enhancement Mode Field Effect Transistor

FEATURES

- 30V , 40A , $R_{DS(ON)}=17\text{m}\Omega$ @ $V_{GS}=10\text{V}$.
 $R_{DS(ON)}=30\text{m}\Omega$ @ $V_{GS}=4.5\text{V}$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability.
- TO-220 & TO-263 package.



ABSOLUTE MAXIMUM RATINGS (Tc=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	30	V
Gate-Source Voltage	VGS	± 20	V
Drain Current-Continuous @ TJ=125°C -Pulsed	ID	40	A
	IDM	120	A
Drain-Source Diode Forward Current	IS	40	A
Maximum Power Dissipation @ Tc=25°C Derate above 25°C	PD	50	W
		0.4	W/°C
Operating and Storage Temperature Range	TJ, TSTG	-65 to 175	°C

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THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Case	$R\theta_{JC}$	3	°C/W
Thermal Resistance, Junction-to-Ambient	$R\theta_{JA}$	62.5	°C/W

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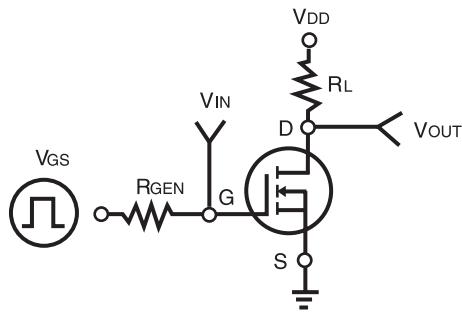


Figure 11. Switching Test Circuit

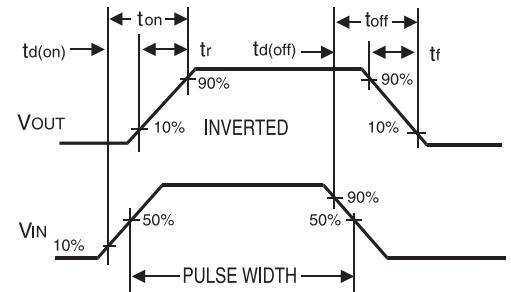


Figure 12. Switching Waveforms

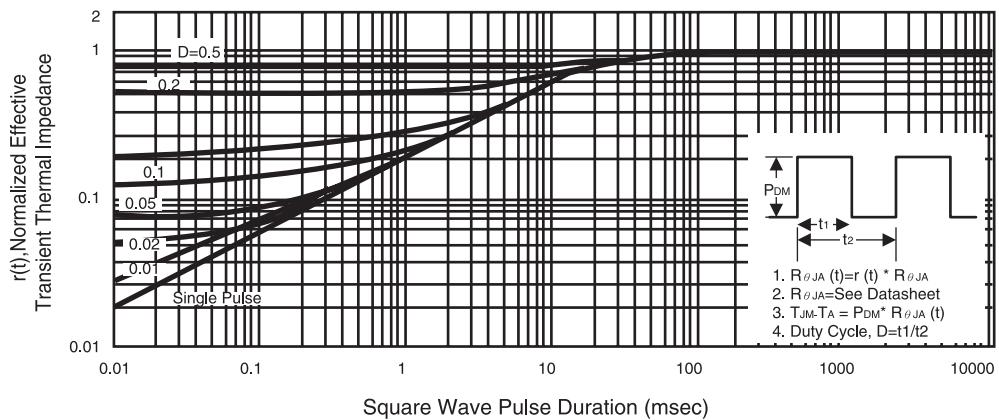


Figure 13. Normalized Thermal Transient Impedance Curve